

Product Change Notification / JAON-28QFPB827

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19-Apr-2023

Product Category:

Broadband Gateway

PCN Type:

Manufacturing Change

Notification Subject:

CCB 5014 Final Notice: Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at ASEM assembly site.

Affected CPNs:

JAON-28QFPB827_Affected_CPN_04192023.pdf JAON-28QFPB827_Affected_CPN_04192023.csv

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at ASEM assembly site.

Pre and Post Change Summary:

		Pre Cl	nange	Post Change				
	Die # 1	Global Foundries, Singapore - Fab		Global Foundries, Singapore - Fa				
	DIC# I	7 (G	F07)	7 (GF07)				
Fabrication		Global	Microchip	Global	Microchip			
Location	Die # 2	Foundries,	Technology	Foundries,	Technology			
	DIE# Z	Singapore - Fab	Colorado – Fab	Singapore - Fab	Colorado – Fab			
		2 (GF02)	5 (MCSO)	2 (GF02)	5 (MCSO)			
		2.204 x 2	.258 mm	1.932x1.860mm				
Die Size	Die # 1	Please see attached pre and post change comparison for Die # 1						
Die Size		Location						
	Die # 2	1.57 x 1	.72 mm	1.57 x 1.72 mm				
Assembly Site		ASE Group -Ma	alaysia (ASEM)	ASE Group -Malaysia (ASEM)				
Wire Material		CuP	dAu	CuPdAu				
Die Attach Material		CRM1	076DS	CRM1076DS				
Molding Compound Material		CEL-9240H	IF10AK-G1	CEL-9240HF10AK-G1				
Lead Frame	Material	C19	4FH	C194FH				

Impacts to Data Sheet:None

Change ImpactNone

Reason for Change:To improve productivity by qualifying a new die size.

Change Implementation Status:In Progress

Estimated First Ship Date:May 20, 2023 (date code: 2320)

Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

		May 2022			>	April 2023			May 2023						
Workweek	1	2	2	2		1	1	1	1	1	1	1	2	2	2
VVOIKWEEK	9	0	1	2		3	4	5	6	7	8	9	0	1	2
Initial PCN Issue				v											
Date				X											
Qual Report									,,						
Availability									X						
Final PCN Issue									,						
Date									Х						

Estimated									
Implementation							Х		l
Date									l

Method to Identify Change: Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:May 24, 2022: Issued initial notification.

April 19, 2023: Issued final notification. Attached the Qualification Report. Provided estimated first ship date to be on May 20, 2023.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

PCN_JAON-28QFPB827_Qual Report.pdf PCN_JAON-28QFPB827_Pre and Post Change_Summary.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

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If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

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Affected Catalog Part Numbers (CPN)

LE9641PQC

LE9651PQC

LE9641PQCT

LE9651PQCT

Date: Tuesday, April 18, 2023



QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN#: JAON-28QFPB827

Date March 30, 2023

Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at ASEM assembly site.



Purpose Qualification of a new die size (1.932x1.860mm) for Die #1 of selected

Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm)

package assembled at ASEM assembly site.

CCB No. 5014

 CN
 E000123107

 QUAL ID
 R2200914 Rev A

 MP CODE
 3413J7M9CA01

 Part No.
 LE9641PQC

Bonding No. BD-000310 Rev.04

Package

Type 48LD VQFN Package size 7 x 7 x 1 mm

Lead Frame

Paddle size 232 x 232 mils

Material C194

Surface Selective AG Plating

Process Etched Lead Lock No

Part Number 170048372135XL

Material

Epoxy CRM1076DS

Wire CuPdAu

Mold Compound CEL-9240HF10AK-G1

Plating Composition Matte Tin



PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
ASEM231800031.000	GF07923119810.000	22314SA

		1
Result	Pass	Fail

48LD VQFN (7x7x1 mm) assembled by ASEM pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

	PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks			
Precondition Prior Perform	Electrical Test: +25°C System: Chroma3650	JESD22- A113	154(0)	0/154		Good Devices			
Reliability Tests (At MSL Level 3)	Bake 150°C, 24 hrs. System: CHINEE	JIP/ IPC/JEDEC		0/154					
	30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR- 3SPH 3x Convection-Reflow 265°C max	J-STD-020E		0/154					
	System: Vitronics Soltec MR1243 Electrical Test: +25°C System: Chroma3650		154(0)	0/154	Pass				
	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X Electrical Test: +25°C System: Chroma3650	JESD22- A118	77(0)	0/77	Pass	Parts had been pre- conditioned at 260°C 77 units			
UNBIASED- HAST	Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X Electrical Test: +25°C System: Chroma3650		77(0)	0/77	Pass				
Wire sweep	Wire sweep Inspection 20 Wires	-	20(0) Wires	0/20	Pass				